## Notice of References Cited

Application/Control No. 10/766,955	Applicant(s)/Patent Under Reexamination YAMASHITA ET AL.		
Examiner	Art Unit		
Helen Rossoshek	2825	Page 1 of 1	

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,960,182 A	09-1999	Matsuoka et al.	703/17
*	В	US-6,152,612 A	11-2000	Liao et al.	703/23
*	O	US-6,279,146 B1	08-2001	Evans et al.	716/18
*	D	US-2002/0059054 A1	05-2002	Bade et al.	703/20
*	ш	US-6,530,054 B2	03-2003	Hollander	714/739
*	F	US-6,629,174 B1	09-2003	Farkas et al.	710/113
*	G	US-2004/0015739 A1	01-2004	Heinkel et al.	714/37
*	Η	US-6,678,645 B1	01-2004	Rajsuman et al.	703/20
*	_	US-6,701,501 B2	03-2004	Waters et al.	716/8
*	J	US-6,810,373 B1	10-2004	Harmon et al.	703/14
*	κ	US-2005/0125754 A1	06-2005	Schubert et al.	716/005
*	L	US-2005/0149898 A1	07-2005	Hakewill et al.	716/018
*	М	US-2005/0289485 A1	12-2005	Willis	716/001

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	α					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Semeria et al., "Methodology for hardware/software co-verification in C/C++", 25-28 Jan. 2000, Design Automation Conference. Proceedings of the ASP-DAC, Asia and South Pacific Page(s):405 - 408
	٧	Carbognani et al., "Qualifying precision of abstract SystemC models using the SystemC verification standard", 2003, Design, Automation and Test in Europe Conference and Exhibition, Page(s):88 - 94 □□
	w	Jindal et al., "Verification of transaction-level SystemC models using RTL testbenches", 24-26 June 2003, Formal Methods and Models for Co-Design, MEMOCODE '03. Proceedings. First ACM and IEEE International Conference on, Page(s):199 - 203
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.